

Experimental $\text{SF}_6^-/\text{SF}_6$ and $\text{Cl}^-/\text{CFCl}_3$ Electron-Attachment Cross Sections in the Energy Range 0–200 meV

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Experimental cross sections for the electron-attachment processes for $\text{SF}_6^-/\text{SF}_6$ and $\text{Cl}^-/\text{CFCl}_3$ are reported in the energy range 0–200 meV by normalizing each attachment line shape to measurement of a thermal rate coefficient. When the same ion states are detected, good agreement is found between present values, for which a monoenergetic electron source is used, and swarm-unfolded results. The present data constitute a new limit for cross sections reported at high resolution at the lowest electron energy.

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The attachment of low-energy electrons to species such as SF_6 , CFCl_3 , and perfluorinated carbon compounds (PFC's) has been the subject of two confluent streams of research. One approach deals with the electron attachment properties of SF_6 and the PFC's with the goal of improving high-voltage-breakdown properties of gases.¹⁻³ The other approach deals with the idea that a high-Rydberg electron is a "free" electron,⁴ and that one may obtain electron-attachment cross sections from collisional ionization rates.⁵⁻⁷

In this Letter we report absolute electron-attachment cross sections for SF_6 and CFCl_3 by the TPSA (threshold photoelectron spectrum by electron attachment) technique.^{8,9} Here, a mixture of Xe atoms and SF_6 molecules in a concentration ratio of about 7:1 is photoionized. One generates thereby *in situ* a narrow band of low-energy electrons by photoionization to the $^2P_{1/2}$ level of Xe^+ ; that is $\text{Xe}(^1S_0) + \hbar\omega \rightarrow \text{Xe}^+(^2P_{1/2}) + e$ (energy ϵ). The electrons e then attach to the admixed SF_6 to form SF_6^- . The SF_6^- ions are drawn out of the collision region, mass analyzed, and their signal detected as a function of the photoionization energy $\hbar\omega$. The electron energy is continuously variable from 0 meV (at the $^2P_{1/2}$ threshold) to, in this study, 200 meV.

Line shapes for electron attachment to SF_6 and CFCl_3 were reported earlier.⁹ In addition to the repeller-box study in that work, further tests were carried out here to ensure that the measured line shapes were independent of pressure, and of voltages on ion-drawout lenses exterior to the collision box. For both attaching gases the dependence of ion signal on pressure of the major Xe component was studied in the range from 1.0×10^{-3} to 7.5×10^{-5} Torr at an energy corresponding to the peak of the profile, and to a point approximately one-third the peak height. In the four measurements the signal was found to vary

linearly with Xe pressure to within an uncertainty of 5%. In addition, many variations of lens voltages were tried, and the SF_6 linewidth measured. The minimum width was found to be the 33 meV reported earlier.⁹ Also, one notes that the attachment shapes in both SF_6 and CFCl_3 rise from onset to peak within about 8 meV.⁹ The stray-field width in the collision chamber must be less than this, since a portion of that 8 meV width arises from the photon bandwidth.

The relative line shapes can be converted to absolute cross sections in either of two distinct ways. In one, a thermal attachment rate coefficient^{10,11} k can be used as a source of calibration by the definition

$$k(\langle\epsilon\rangle) = (2/m)^{1/2} \int_0^\infty \sigma_A(\epsilon) \epsilon^{1/2} f(\epsilon) d\epsilon \text{ cm}^3/\text{s}, \quad (1)$$

where m is the electron mass, $\sigma_A(\epsilon)$ the electron-attachment cross section, and $f(\epsilon)$ a Maxwellian electron-energy distribution at the mean energy $\langle\epsilon\rangle$ corresponding to the SF_6 or CFCl_3 temperature (usually 300 K). In the second approach use is made of $\text{SF}_6^-/\text{SF}_6$ or $\text{Cl}^-/\text{CFCl}_3$ electron-attachment cross sections at higher energies ($\epsilon \geq 40$ meV) which have been unfolded from swarm-measured attachment rates.¹⁻³ These cross sections serve as calibration points for placing the entire range of $\sigma_A(\epsilon)$ on the absolute scale.

We opt for the first method of calibration because (a) the attachment rate k in Eq. (1) is accurately known for SF_6 and CFCl_3 , and (b) the assumption of a Maxwellian distribution having been attained at a fixed gas temperature seems to us to be less ambiguous than results of a swarm-unfolding procedure in which the cross section depends strongly upon the calculated electron-energy distribution of the swarm (see below).

From earlier results⁹ the measured production yield $P(E_0)$ of ions can be written as the convolution of the spectrometer slit function S with the

product of the attachment cross section $\sigma_A(\epsilon)$ and the Xe photoionization cross section σ_I , or

$$P(E_0) = \int_0^\infty S(E_0 - E_t - \epsilon) \sigma_I(E_t + \epsilon) \sigma_A(\epsilon) d\epsilon, \quad (2)$$

where E_t is the $\text{Xe}^+ (^2P_{1/2})$ photoionization threshold energy (13.436 eV) and E_0 the incident photon energy at the center of the bandpass.

In practice, two exponential slopes¹² γ_1 and γ_2 ,

each over a separate energy range, were used to fit the observed⁹ $P(E_0)$, so that $k(\langle\epsilon\rangle)$ contained contributions from each range. If we assume the form $\sigma_A(\epsilon) \sim \exp(-\epsilon/\gamma_i)$, and a Maxwellian distribution for $f(\epsilon)$ given by

$$f(\epsilon) = (2/\sqrt{\pi})(3/2\langle\epsilon\rangle)^{3/2} \epsilon^{1/2} \exp(-3\epsilon/2\langle\epsilon\rangle),$$

integration of Eq. (1) can be carried out by parts to give

$$k(\langle\epsilon\rangle) = [(1.233 \times 10^8 \sigma_0) / \langle\epsilon\rangle^{3/2}] \sum_{i=1}^2 a_i \Gamma_i^2 [1 + \epsilon/\gamma_i] \exp(-\epsilon/\Gamma_i) \Big|_{\epsilon_{ui}}^{\epsilon_{li}}, \quad (3)$$

where ϵ_{li} and ϵ_{ui} refer to lower and upper energies in each range i . The limits ϵ_{l1} and ϵ_{u2} were, respectively, zero and infinity by Eq. (1). The intermediate limit ϵ_{i2} ($=\epsilon_{u1}$) was just the matching point of the two experimental pieces. It, as well as the slopes γ_1 and γ_2 , and the relative amplitude a_2 of the two exponential sections ($a_1=1.0$) were computed by an exponential curve fitting to $P(E_0)$ in Eq. (2). The resultant fit was within the statistical error in $P(E_0)$ except in the range 0–6 meV where the fit lay 10% below the data. (Use of a third exponential in this range would improve agreement. However, this was not done in light of the uncertainties involved at $\epsilon \lesssim 4$ meV.) The normalization constant to the absolute cross-section scale is just σ_0 .

Results of the fit for the $\text{SF}_6^-/\text{SF}_6$ and $\text{Cl}^-/\text{CFCl}_3$ attachment processes are, respectively, the following:

$$\sigma(\epsilon) = 5.20 \times 10^{-14} \times \begin{cases} \exp(-\epsilon/44.4) \text{ cm}^2, & 0 \leq \epsilon \leq 45 \text{ meV} \\ 0.868 \exp(-\epsilon/51.6) \text{ cm}^2, & 45 \leq \epsilon \leq 200 \text{ meV}, \end{cases} \quad (4)$$

$$\sigma(\epsilon) = 3.36 \times 10^{-15} \times \begin{cases} \exp(-\epsilon/34.9) \text{ cm}^2, & 0 \leq \epsilon \leq 63 \text{ meV} \\ 0.569 \exp(-\epsilon/50.7) \text{ cm}^2, & 63 \leq \epsilon \leq 200 \text{ meV}. \end{cases} \quad (5)$$

The values of $k(\langle\epsilon\rangle)$ used in the calibration were¹¹ $2.28 \times 10^{-7} \text{ cm}^3/\text{s}$ with an estimated uncertainty of less than 5% for SF_6 , and³ $(1.21 \pm 0.12) \times 10^{-8} \text{ cm}^3/\text{s}$ for CFCl_3 , with $\langle\epsilon\rangle = 38.8$ meV (300 K). Results for SF_6 and CFCl_3 are shown in Figs. 1 and 2, respectively. In both cases $\sigma_A(\epsilon)$ is found to be a maximum at 0 meV, to within an experimental uncertainty of 4 meV at threshold. The shaded regions represent uncertainties due to (a) statistical error in $P(E_0)$, (b) error in the measurement of $k(\langle\epsilon\rangle)$, and (c) error in the fit to $P(E_0)$. These were combined in quadrature to give overall errors (12–18)% (for $\text{SF}_6^-/\text{SF}_6$) and (15–18)% (for $\text{Cl}^-/\text{CFCl}_3$), where the smaller error refers to the range 0–60 meV, that error increasing linearly to the larger value at 200 meV.

In Fig. 1 the present results are compared to the data of Christodoulides *et al.*² and McCorkle *et al.*³ The last two sets of cross sections were unfolded from the same swarm attachment rates.¹ Differences between the two sets, in both magnitude and shape, lie in the use of different electron-energy distribution functions for N_2 .^{3, 13} Good agreement is seen between the TPSA and newer swarm cross sections. The present meas-

urements provide new data in the region $0 \leq \epsilon \leq 10$ meV, and the fact that $\sigma_A(\epsilon)$ has its maximum within 4 meV of 0 meV has important consequences for the temperature dependence of the attachment rate coefficient.¹¹ Attachment cross sections are also given by Kline *et al.*¹⁴ These cross sections are in somewhat better agreement with data based on the newer N_2 distribution function³ (Fig. 1, open circles), and with the present results.

The differences of the present data with the swarm-unfolded cross sections^{2, 3} point up an important result of this work, namely that the present $\sigma_A(\epsilon)$'s do not require a solution of Boltzmann's equation for obtaining a swarm electron-energy distribution function. One need only assume that a Maxwellian distribution has been attained at 300 K in the attachment-rate measurements.^{10, 11} Even this assumption is not overly critical. For example, one may use a Druyvesteyn¹⁵ form for $f(\epsilon)$ in Eq. (1), and carry out the integration in terms of error functions. The value of σ_0 obtained now is 0.76 times that of the Maxwellian case, indicating an insensitivity of

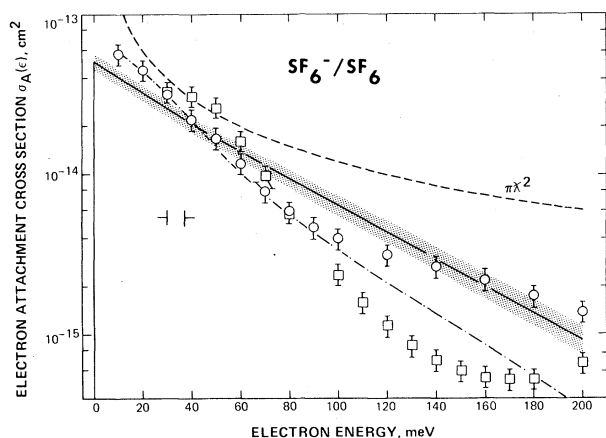


FIG. 1. Electron-attachment cross sections for $\text{SF}_6^-/\text{SF}_6$. Present experimental measurements are given as the solid line with errors indicated by shading. Open squares are swarm-unfolded measurements of Christodoulides *et al.* (Ref. 2) and open circles are those of McCorkle *et al.* (Ref. 3), which use two different electron-energy distributions. These data include production of all negative ions from SF_6 , in addition to SF_6^- . Results of Kline *et al.* (Refs. 12 and 14) (dot dashed line) are accurate for energies $\epsilon \geq 100$ meV, but the shape in the range $10 \leq \epsilon < 100$ meV is instrumental. Also shown are the electron energy resolution in the present data, and the maximum s -wave capture cross section $\pi\kappa^2$ (dashed line).

$\sigma_A(\epsilon)$ to the form of $f(\epsilon)$, relative to the dependence of swarm values^{2,3} on requirements and assumptions (necessary cross sections, two-term versus multiterm solutions) incurred by a Boltzmann-equation approach.

New data for the region $0 \leq \epsilon < 40$ meV are given for the attachment process for $\text{Cl}^-/\text{CFCl}_3$ in Fig. 2, and compared with swarm results of McCorkle *et al.*³ We note here, however, that the magnitudes of the TPSA and swarm cross sections at the lower energies ($\epsilon < 100$ meV) are not strictly independent, since the thermal rate of McCorkle *et al.*³ was obtained by averaging their swarm-unfolded cross sections with a Maxwellian $f(\epsilon)$, whereas for SF_6 it was derived from a $k(\langle\epsilon\rangle)$ measured in a separate experiment.^{10, 11} However, these results demonstrate another principal feature of the TPSA method in that $\sigma_A(\epsilon)$ in both Figs. 1 and 2 refer to a particular channel for negative-ion formation. That channel is SF_6^- from SF_6 in Fig. 1, and Cl^- from CFCl_3 in Fig. 2. The swarm-unfolded data reflect all open channels for attenuation of the electron swarm. For energies $\epsilon < 100$ meV, the swarm and TPSA data refer to the same

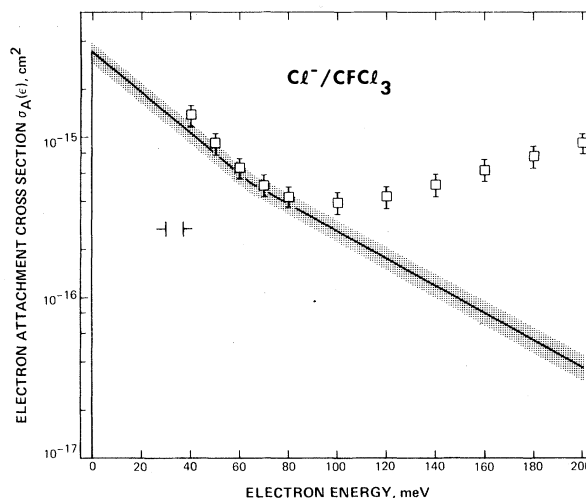


FIG. 2. Electron-attachment cross sections for CFCl_3 . Present results are given as the solid line with errors indicated by shading. Open squares are swarm-unfolded data of McCorkle *et al.* (Ref. 3) for the production of all negative ions. The difference between the two sets of data at $\epsilon \geq 100$ meV arises from channel(s) for negative-ion production other than for $\text{Cl}^-/\text{CFCl}_3$.

channels since the thermal electron attachment process is predominant. At larger energies, one can expect other channels to contribute to the swarm-unfolded data but not to the TPSA data. For example, the $\text{SF}_5^-/\text{SF}_6$ process starts at thermal energies,¹⁶ and attains a broad maximum at¹ 0.35 eV. This is probably the reason for the slower falloff in the swarm data at $\epsilon > 100$ meV in Fig. 1. Likewise, a new channel is almost certainly responsible for the increase in negative-ion production in CFCl_3 (Fig. 2) for $\epsilon > 100$ meV. From our results, we conclude that this new channel cannot be Cl^- formation as found by Curran,¹⁷ but rather to some other negative ion from CFCl_3 .

The present results appear to have some relevance to the study of collisional ionization of high-Rydberg (HR) atoms by SF_6 .⁴⁻⁷ From Matsuza-wa's theory,⁴ the rate constant (i.e., cross section averaged over a velocity distribution of the colliding partners) for ionization of a HR atom should be equal to that of attachment of the "nearly free" HR electron to the attaching partner. This rate correspondence has been demonstrated by Foltz *et al.*⁶ and Dimicoli and Botter.⁷ Cross sections have been reported⁵⁻⁷ by dividing the rate constant by some average relative velocity of the colliding partners. These cross sections,

of the order 10^{-12} cm², have been somewhat loosely referred to as attachment cross sections (see, for example, the abstract of Ref. 4) since a HR electron is "nearly free." The present results indicate that the maximum cross section for attachment in which the electron is *truly* free is 5.20×10^{-14} cm² for SF₆⁻/SF₆, and 3.36×10^{-15} cm² for Cl⁻/CFCl₃. These are 10^{-2} – 10^{-3} the reported collisional ionization cross sections.

However, the idea of a HR electron behaving as a free electron is somewhat unsatisfying on a simple energetic principle. One has to overcome the binding energy (5–50 meV, say) of that electron relative to its core. Indeed, recent experiments⁷ have shown that this binding energy has to be taken into account, and that the positive-ion core does play a role in the electron transfer. Such core effects are absent in the TPSA technique, thus in the $\sigma_A(\epsilon)$ reported here.

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